

# **Function Module SDx**



Model:	SDx
Description:	Synchro/Resolver Measurement

## Specifications

Number of Channels:	4 Channels
Resolution:	24-bit
Input Format:	Synchro to Digital (S/D), Resolver to Digital (R/D), Programmable
Input Voltage:	2 - 90 Vrms
Excitation Voltage:	2 - 115 Vrms
Accuracy:	±1 arc-minute for single-speed inputs
Frequency Range:	SD1 and SD5 - 47 Hz - 1 kHz,
	SD2: 1 kHz-5 kHz,
	SD3: 5 kHz-10 kHz,
	SD4: 10 kHz-20 kHz
Phase Shift:	Up to ±60°.
Self-Test:	Built-in wraparound self-test.
Power:	5 VDC @ 1 A
Weight:	2.7 oz. (75 g)

#### **Programmable Features:**

- Bandwidth (Hz)
- Single, two or multi-speed configuration
- Angle change alert
- Signal Loss Threshold
- Reference Loss Threshold
- Configure each channel for Synchro or Resolver measurement

### **Measured signals:**

- Individual channel input Reference and Signal voltages
- Individual channel input Reference Frequency

#### **Additional Features**

Available data in the FIFO buffer can be retrieved, one word at a time (32-bits).

### Built-In Test (BIT) / Diagnostic Capability

SD1-SD5 incorporate major diagnostics that ensure that the user is alerted to channel malfunction. This approach reduces bus traffic, because the Status Registers need not be constantly polled. Three different tests (one on-line and two off-line) can be selected.

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The **Online (D2)** Test initiates automatic background BIT testing. Each channel is checked every 5° to a testing accuracy of 0.05° and each Signal and Reference is always monitored. Any failure triggers an Interrupt (if enabled) and the results are available in status registers. The testing is totally transparent to the user.

The **Offline (D3)** Test initiates a BIT test that disconnects all channels from the outside world and connects them across an internal stimulus that generates and tests 36 different angles to a test accuracy of 0.1°. Results can be read from registers and external reference is not required. Any failure triggers an Interrupt (if enabled

The **Offline (D0)** Test is used to check the card and the system interface. All channels are disconnected from the outside world, allowing the user to write any angle

Basic S	/D FI	FO Inte	rrupts											
Chan.	n. Configuration						Measurements							
Chan.	Mode	Ang. Delta	Ref. Thresh	VLL Thresh.	BW Sel.	BandWidth	Latched	Angle	Velocity	Freq.	Sig. Volt.	Ref. Volt.	Sin	Cos
✓ All	Syn 💌				Manua 👻									
✔ 1	Rsl 💌	0.0000	0.00	0.00	•	0		0.0000	+0.0	0	0.00	0.00	0.000	0.000
✓ 2	Rsl 💌	0.0000	0.00	0.00	•	0		0.0000	+0.0	0	0.00	0.00	0.000	0.000
✔ 3	Rsl 💌	0.0000	0.00	0.00	•	0		0.0000	+0.0	0	0.00	0.00	0.000	0.000
✔ 4	Rsl 💌	0.0000	0.00	0.00	•	0		0.0000	+0.0	0	0.00	0.00	0.000	0.000
Refresh     Display Hex     Software Trigger     Enable D0 Test     0														
$\bigcirc$		,	Au	Auto-Refresh     100     Module FPGA Rev:     0.0     Enable D2 Test     0x00										

#### Embedded Soft Panel (ESP) allows easy access to each channel information

Status - Latched/Realtime										
En.	R. Loss	S. Loss	BIT	L. Loss	D. Angle	Open	Short			
	00	00	00	00	00	00	00			
	00	00	00	00	00	00	00			
	00	00	00	00	00	00	00			
	00	00	00	00	00	00	00			
	Clear	Clear	Clear	Clear	Clear	Clear	Clear			



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